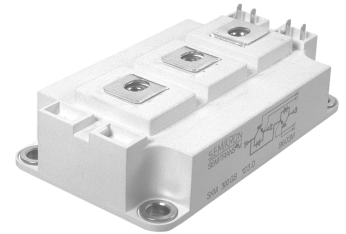


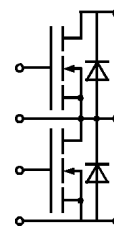
Absolute Maximum Ratings		Values	Units
Symbol	Conditions ¹⁾		
V _{DS}		100	V
V _{DGR}	R _{GE} = 20 kΩ	100	V
I _D	T _{case} = 25 °C / 80 °C	400 / 300	A
	T _{case} = 100 °C	250	A
I _{DM}	1 ms	1140	A
V _{GS}		± 20	V
P _D		1040	W
T _J , (T _{stg})		-40 ... +150 (125)	°C
V _{isol}	AC, 1 min., 200 μA	2 500	V
humidity	DIN 40 040	Class F	
climate	DIN IEC 68 T.1	40/125/56	
Inverse Diode			
I _F = -I _D		380	A
I _{FM} = -I _{DM}	10 μs	1140	A

SEMITRANS® M Power MOSFET Modules 300 A, 100 V, 3,5 mΩ

SKM 313 B 010



SEMITRANS M3



Features

- N Channel, enhancement mode
- Short internal connections and low inductance case avoid oscillations
- Isolated copper baseplate using Al₂O₃ ceramic Direct Copper Bonding Technology (DCB)
- All electrical connections on top for easy busbaring
- Large clearance (13 mm) and creepage distances (20 mm)
- UL recognized file no. E63 532

Typical Applications

- DC servo and robot drives
- DC choppers
- Battery vehicles
- UPS equipment
- Plasma cutting
- Not suitable for linear amplification

This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.

Suitable mounting hardware:
Ident No. 33321100
(for 10 SEMITRANS 3)
Screws → B 6 – 4

Characteristics		min.	typ.	max.	Units
Symbol	Conditions ¹⁾				
V _{(BR)DSS}	V _{GS} = 0, I _D = 0,5 mA	100	–	–	V
V _{GS(th)}	V _{GS} = V _{DS} , I _D = 5 mA	2,1	3,0	4,0	V
I _{DSS}	V _{GS} = 0 } T _J = 25 °C	–	–	100	μA
	V _{DS} = 100 V } T _J = 125 °C	–	–	1000	μA
I _{GSS} ³⁾	V _{GS} = 20 V, V _{DS} = 0	–	–	100	nA
R _{DS(on)}	V _{GS} = 10 V, I _D = 300 A	–	3	3,5	mΩ
g _{fs}	V _{DS} = 25 V, I _D = 300 A	150	200	–	S
C _{CHC}	} V _{GS} = 0 } V _{DS} = 25 V } f = 1 MHz	–	–	700	pF
C _{iss}		–	24	32	nF
C _{oss}		–	7,3	11	nF
C _{rss}		–	4,3	6,5	nF
L _{DS}		–	–	20	nH
t _{d(on)}	} V _{DD} = 30 V } I _D = 250 A } V _{GS} = ± 10 V } R _G = 4,7 Ω	–	100	–	ns
t _r		–	100	–	ns
t _{d(off)}		–	700	–	ns
t _f		–	250	–	ns
Inverse Diode					
V _{SD}	I _F = 300 A, V _{GS} = 0 V	–	1,2	1,5	V
t _{rr}	T _J = 25 °C ³⁾	–	160	–	ns
	T _J = 150 °C ³⁾	–	–	–	ns
Q _{rr}	T _J = 25 °C ³⁾	–	10	–	μC
I _{RR}	T _J = 150 °C ³⁾	–	–	–	A
Thermal characteristics					
R _{thjc}	per MOSFET	–	–	0,12	°C/W
R _{thch}	M ₁ , surface 10 μm, per module	–	–	0,038	°C/W

Mechanical Data					
M ₁	to heatsink, SI Units (M6)	3	–	5	Nm
	to heatsink, US Units	27	–	44	lb.in.
M ₂	for terminals, SI Units (M6)	2,5	–	5	Nm
	for terminals, US Units	22	–	44	lb.in.
a		–	–	5x9,81	m/s ²
w		–	–	325	g
Case	→ B 5 – 46			D 56	

¹⁾ T_{case} = 25 °C, unless otherwise specified

³⁾ I_F = 300 A, V_R = 100 V, -di_F/dt = 100 A/μs

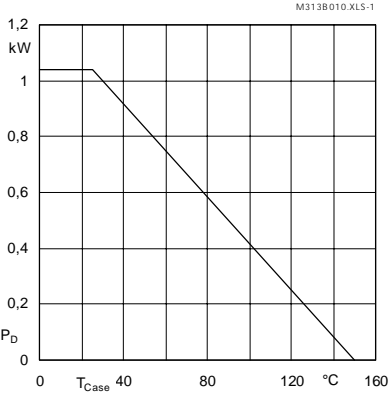


Fig. 1 Rated power dissipation vs. temperature

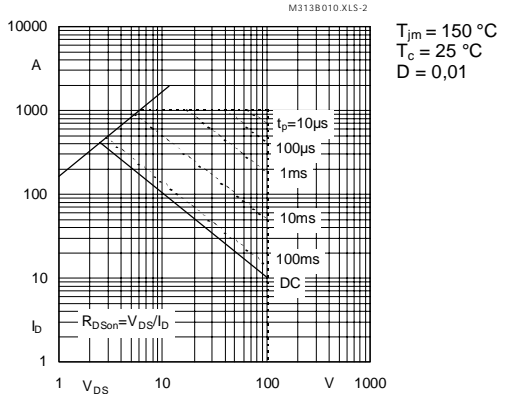


Fig. 2 Maximum safe operating area, single pulse

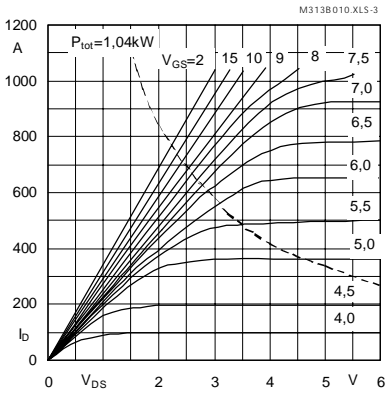


Fig. 3 Output characteristic, $t_p = 80 \mu s$, $T_j = 25 \text{ }^\circ\text{C}$

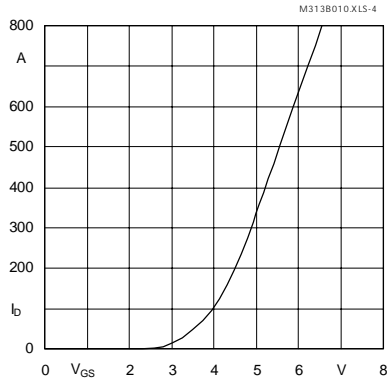


Fig. 4 Transfer characteristic, $t_p = 80 \mu s$, $V_{DS} = 25 \text{ V}$

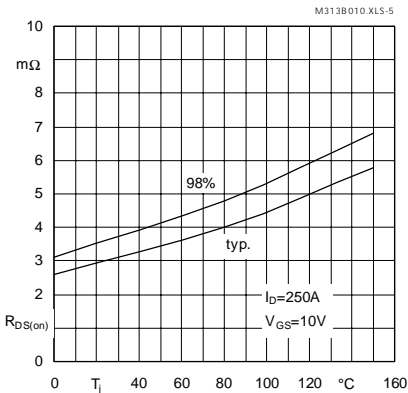


Fig. 5 On-resistance vs. temperature

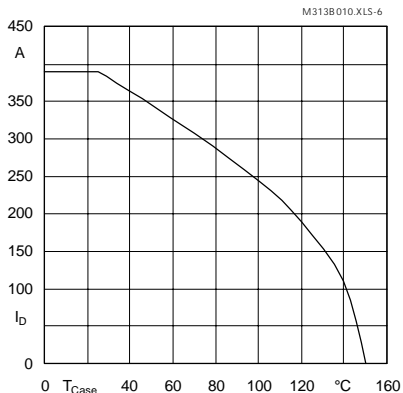


Fig. 6 Rated current vs. temperature

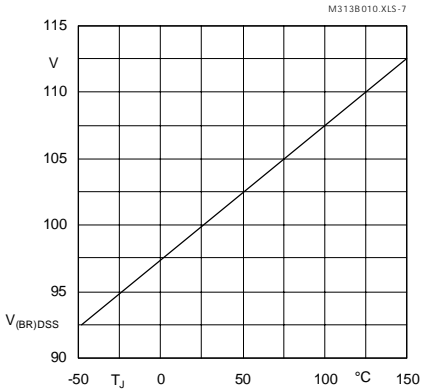


Fig. 7 Breakdown voltage vs. temperature

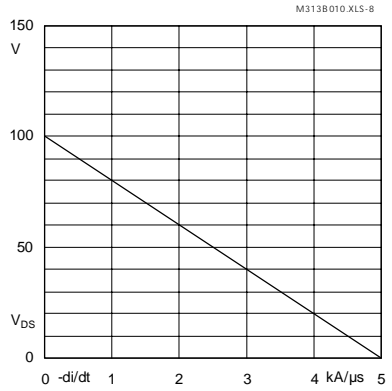


Fig. 8 Drain-source voltage derating (L_{DS})

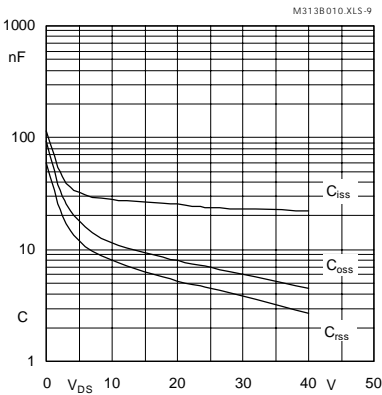


Fig. 9 Typ. capacitances vs. drain-source voltage

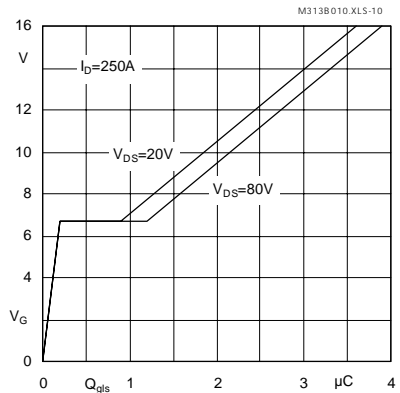


Fig. 10 Gate charge characteristic, $I_{DP} = 250 \text{ A}$

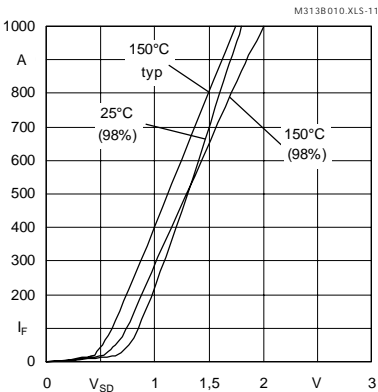


Fig. 11 Typ. Diode forward characteristic, $t_p = 80 \mu\text{s}$

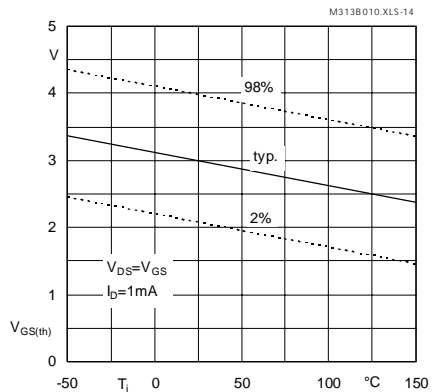


Fig. 14 Gate-source threshold voltage

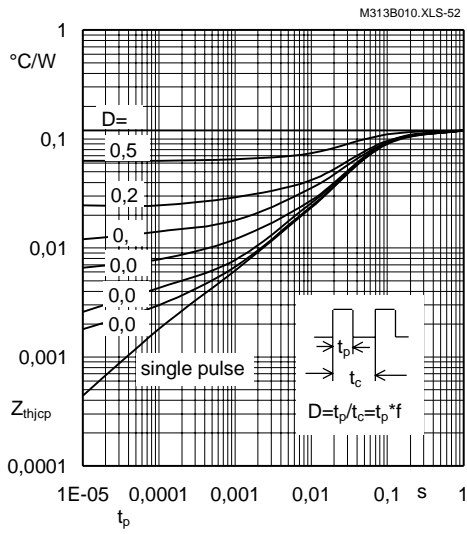


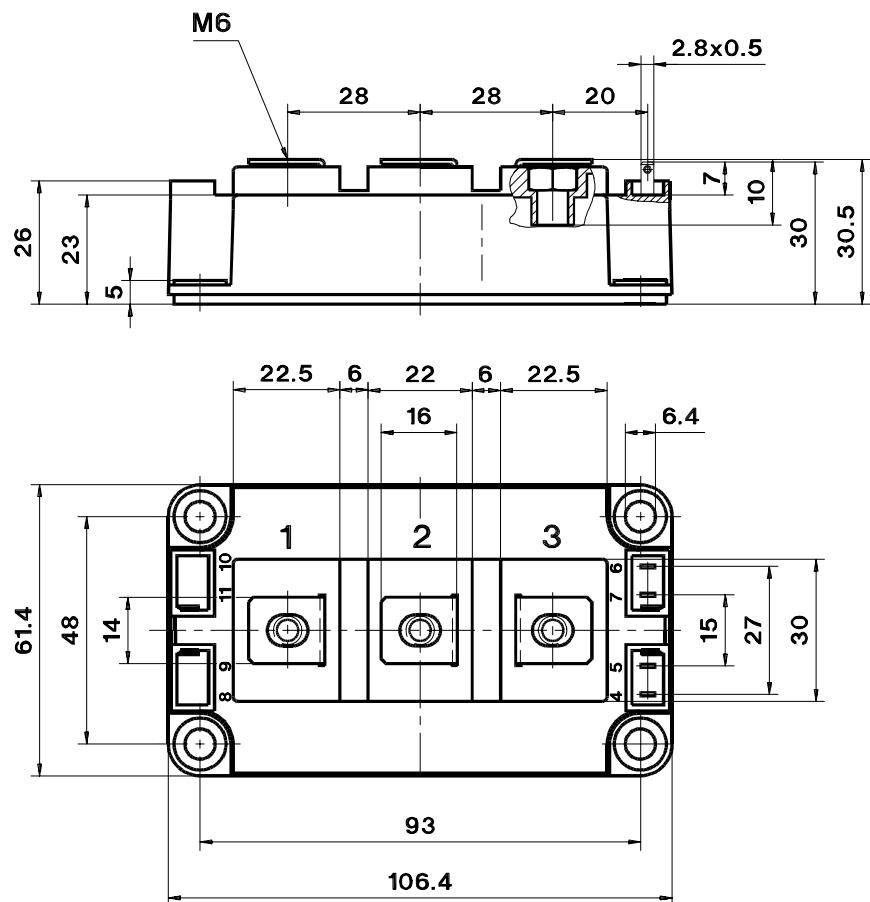
Fig. 52 Thermal impedance under pulse conditions

SEMITRANS M 3

Case D 56

SKM 313 B 010

CASED56



Dimensions in mm